

Polishing with Advanced Tool Paths to Optimize Surface Micro-structure and PSD

#### Christina Dunn, David Walker and John Kelchner

#### Zeeko Technologies, LLC

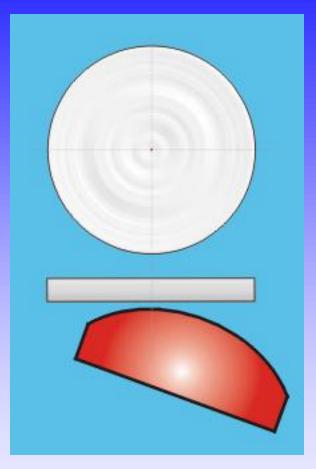
1801 Kalberer Road, Suite K-100 West Lafayette, IN 47906 Tel: 765-775-1010

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### **Basis of the Zeeko Polishing Process**

- Spherical "bonnet" creates a localized area of material removal of variable size ("influence function")
- Spot size is controlled independently by varying:
  - The axial position of the tool WRT the part, and therefore the degree to which the membrane is compressed against the part
  - The internal pressure of the working fluid within the tool is controlled separately





## Tooling

The spherical bonnet tooling:

- is covered with standard polishing pads (e.g. polyurethane)
- is pressed into the surface of the workpiece by displacement ∆z, creating a contact spot of known diameter
- is worked with standard polishing consumables (e.g. cerium oxide)
- delivers volumetric removal rates up to a few cubic millimeters per minute





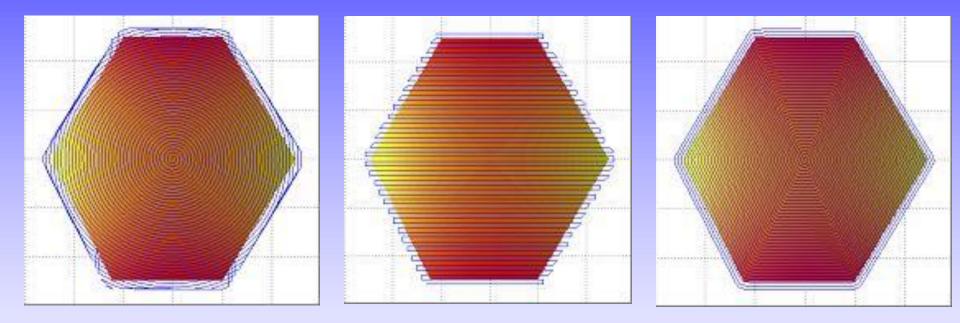


#### Zeeko Polishing Advantages

#### The Zeeko Classic polishing process:

- Uses standard polishing pads and slurries
- Pre-polishes from the ground blank condition
- Capable of polishing complex freeform geometries
- Able to polish a plethora of materials including optical glasses, ceramics and metals
- Is deterministic, resulting in reduced production times due to its high removal rate and repeatability

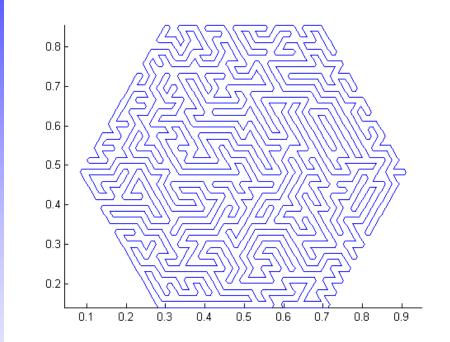
### Tool paths





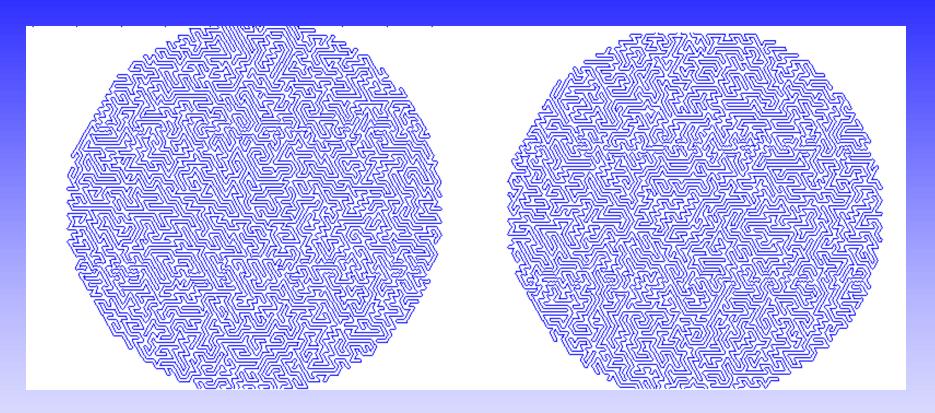
### The unicursal random tool path

- Never crosses itself
- Completely new pattern
  with each iteration
- Can be used with any continuous surface
- This tool path is compatible with Zeeko's *Precessions* software for corrective polishing





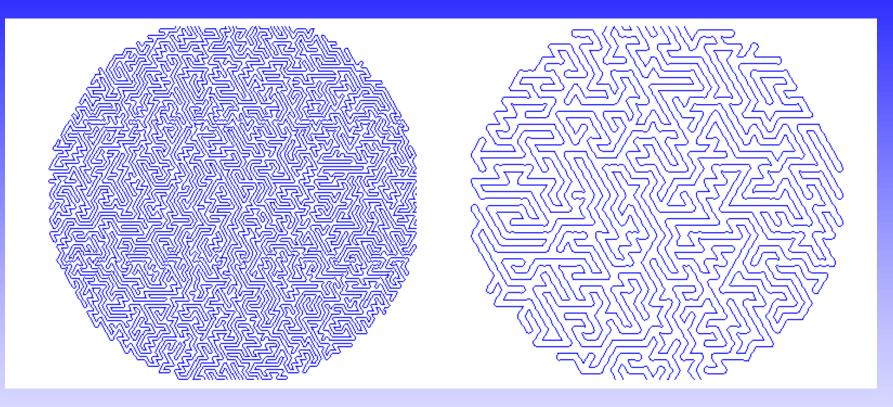




 A new pattern is produced with each iteration of the algorithm.

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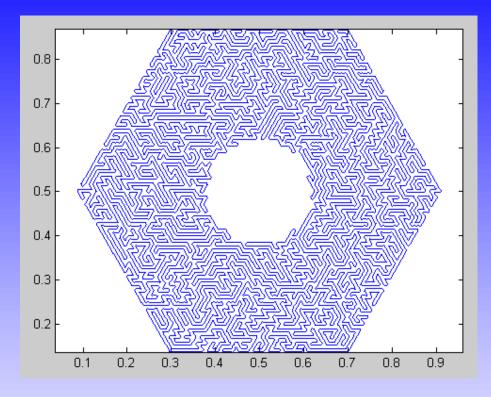




• The density of the pattern can be varied.

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• The algorithm can be used with any continuous surface.

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Two experiments are presented in this talk . . .

- A comparison of polishing with raster and random tool paths, with all other variables held constant
- Improving the PSD of a raster-polished region using a random tool path

# A comparison between raster and random tool paths

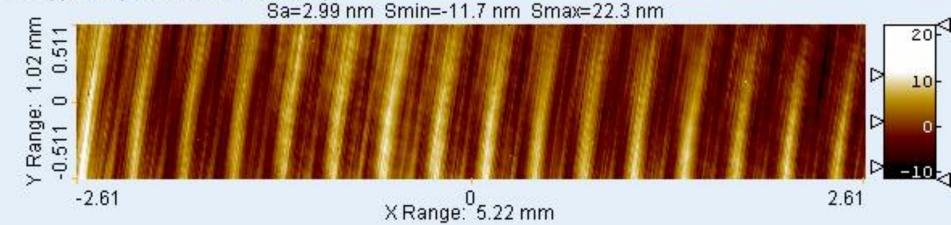
- Two 20-mm diameter spots were polished on a pitch-polished flat part
- The pattern spacing on both paths was 0.35 mm.
- All other parameters were equal.

Feed rate: 100 mm/min H-axis speed: 300 rpm Precess angle: 15 10 mm spot 80 mm bonnet Z-offset: 0.16 mm Polishing time: 30 min



### Raster polished region

#### C:\Copy of MapvueAE\Data\TEMP.map



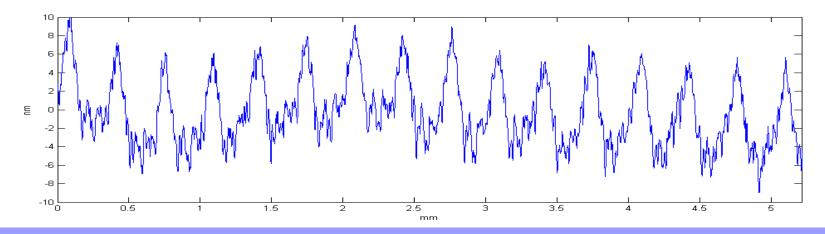
#### Random polished region

C:\Copy of MapvueAE\DataC:\Copy of MapvueAE\Data\TEMP.map Sa=2.53 nm Smin=-136 nm Smax=15.7 nm

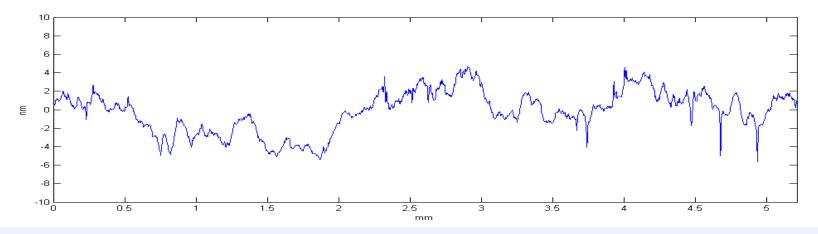


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#### Raster polished region profile



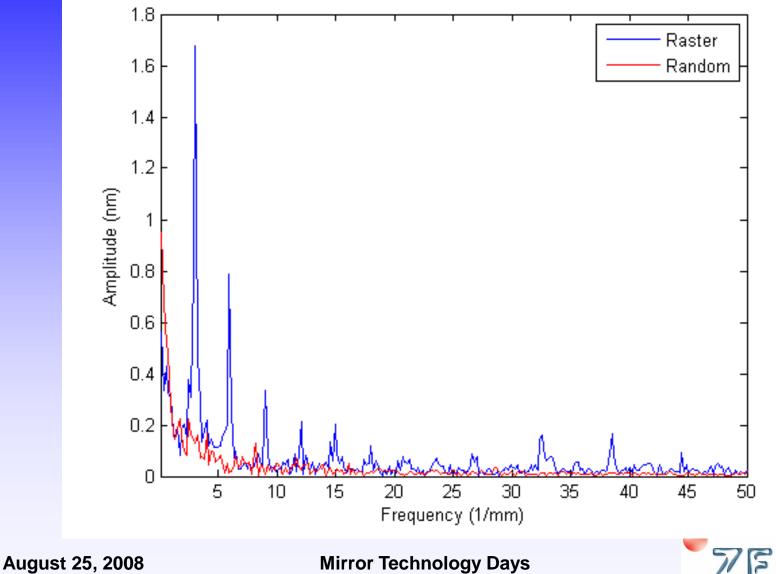
#### Random polished region profile



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#### **PSD** Comparison

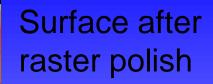


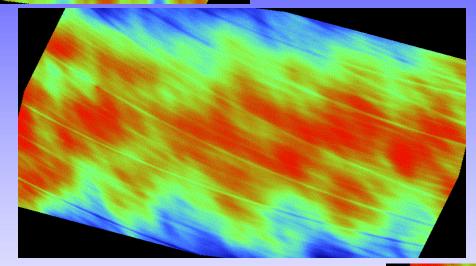


# Improving PSD on a raster polished surface

- A 35mm diameter area on a glass flat was polished with a raster path to produce a surface with a periodic midspatial frequency feature.
- This region was then re-polished twice using random tool paths, resulting in an improvement in PSD.

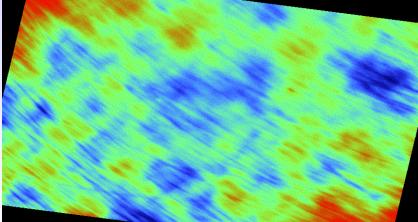




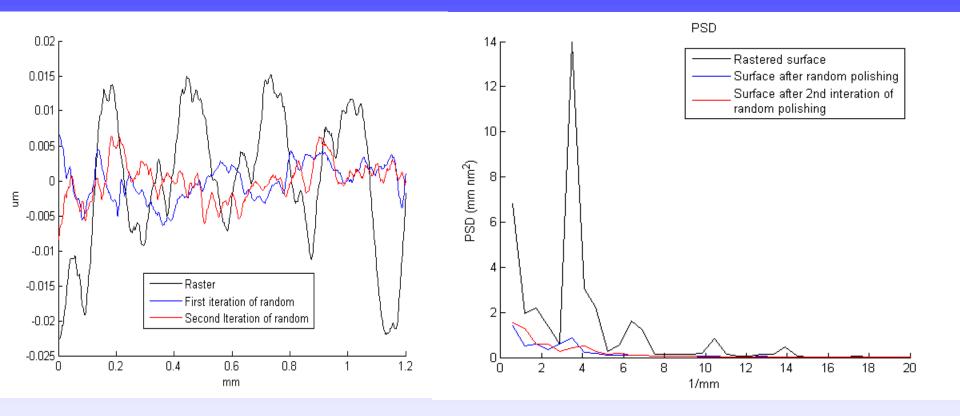


## Surface after 1st random polish

#### Surface after 2nd random polish



#### **Surface characteristics**





#### Surface texture statistics

	Ra (nm)	Rq (nm)	Rt (nm)
Rastered surface	8.10	10.29	114.47
After 1st random polish	6.55	7.85	43.37
After 2nd random polish	3.95	5.24	35.21



#### Future Work

- Improve the performance of the random tool path by using advanced interpolation methods in the CNC controller of the Zeeko machines.
- Integrate random tool paths with edge control.
- Integrate the random tool path into Zeeko's *Precessions*<sup>™</sup> software for corrective polishing.



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